

**Search Notes**

Application/Control No.

10/667,511

Examiner

Binh X. Tran

Applicant(s)/Patent under  
Reexamination

MIYAMORI ET AL.

Art Unit

1765

**SEARCHED**

Class	Subclass	Date	Examiner
438	697	1/11/2006	BT
438	703	1/11/2006	BT
438	722	1/11/2006	BT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
438	697	1/11/2006	BT
438	703	1/11/2006	BT
438	722	1/11/2006	BT

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Update search using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	1/11/2006	BT